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### Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	576
Number of Logic Elements/Cells	1368
Total RAM Bits	18432
Number of I/O	192
Number of Gates	30000
Voltage - Supply	3V ~ 3.6V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	256-BBGA
Supplier Device Package	256-PBGA (27x27)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/xilinx/xcs30xl-5bg256c">https://www.e-xfl.com/product-detail/xilinx/xcs30xl-5bg256c</a>

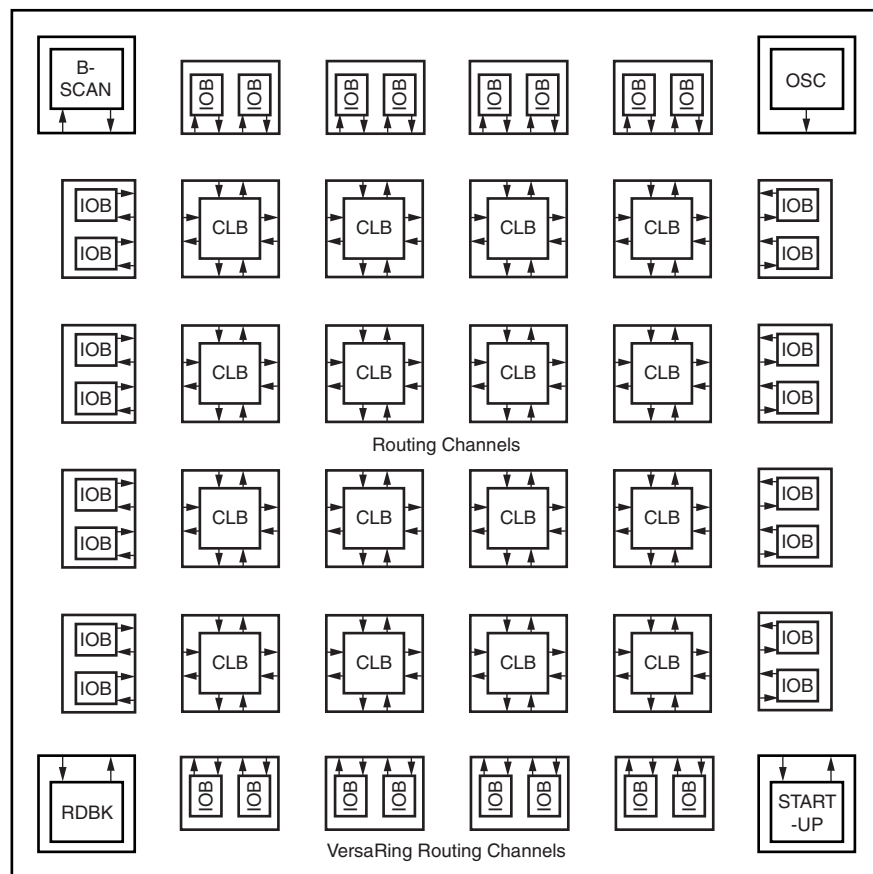
## General Overview

Spartan series FPGAs are implemented with a regular, flexible, programmable architecture of Configurable Logic Blocks (CLBs), interconnected by a powerful hierarchy of versatile routing resources (routing channels), and surrounded by a perimeter of programmable Input/Output Blocks (IOBs), as seen in **Figure 1**. They have generous routing resources to accommodate the most complex interconnect patterns.

The devices are customized by loading configuration data into internal static memory cells. Re-programming is possible an unlimited number of times. The values stored in these

memory cells determine the logic functions and interconnections implemented in the FPGA. The FPGA can either actively read its configuration data from an external serial PROM (Master Serial mode), or the configuration data can be written into the FPGA from an external device (Slave Serial mode).

Spartan series FPGAs can be used where hardware must be adapted to different user applications. FPGAs are ideal for shortening design and development cycles, and also offer a cost-effective solution for production rates well beyond 50,000 systems per month.



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Figure 1: Basic FPGA Block Diagram

Spartan and Spartan-XL devices provide system clock rates exceeding 80 MHz and internal performance in excess of 150 MHz. In addition to the conventional benefit of high volume programmable logic solutions, Spartan series FPGAs also offer on-chip edge-triggered single-port and dual-port RAM, clock enables on all flip-flops, fast carry logic, and many other features.

The Spartan/XL families leverage the highly successful XC4000 architecture with many of that family's features and benefits. Technology advancements have been derived from the XC4000XLA process developments.

## Logic Functional Description

The Spartan series uses a standard FPGA structure as shown in [Figure 1, page 2](#). The FPGA consists of an array of configurable logic blocks (CLBs) placed in a matrix of routing channels. The input and output of signals is achieved through a set of input/output blocks (IOBs) forming a ring around the CLBs and routing channels.

- CLBs provide the functional elements for implementing the user's logic.
- IOBs provide the interface between the package pins and internal signal lines.
- Routing channels provide paths to interconnect the inputs and outputs of the CLBs and IOBs.

The functionality of each circuit block is customized during configuration by programming internal static memory cells. The values stored in these memory cells determine the logic functions and interconnections implemented in the FPGA.

## Configurable Logic Blocks (CLBs)

The CLBs are used to implement most of the logic in an FPGA. The principal CLB elements are shown in the simplified block diagram in [Figure 2](#). There are three look-up tables (LUT) which are used as logic function generators, two flip-flops and two groups of signal steering multiplexers. There are also some more advanced features provided by the CLB which will be covered in the [Advanced Features Description, page 13](#).

### Function Generators

Two 16 x 1 memory look-up tables (F-LUT and G-LUT) are used to implement 4-input function generators, each offering unrestricted logic implementation of any Boolean function of up to four independent input signals (F1 to F4 or G1 to G4). Using memory look-up tables the propagation delay is independent of the function implemented.

A third 3-input function generator (H-LUT) can implement any Boolean function of its three inputs. Two of these inputs are controlled by programmable multiplexers (see box "A" of [Figure 2](#)). These inputs can come from the F-LUT or G-LUT outputs or from CLB inputs. The third input always comes from a CLB input. The CLB can, therefore, implement certain functions of up to nine inputs, like parity checking. The three LUTs in the CLB can also be combined to do any arbitrarily defined Boolean function of five inputs.

### Output Multiplexer/2-Input Function Generator (Spartan-XL Family Only)

The output path in the Spartan-XL family IOB contains an additional multiplexer not available in the Spartan family IOB. The multiplexer can also be configured as a 2-input function generator, implementing a pass gate, AND gate, OR gate, or XOR gate, with 0, 1, or 2 inverted inputs.

When configured as a multiplexer, this feature allows two output signals to time-share the same output pad, effectively doubling the number of device outputs without requiring a larger, more expensive package. The select input is the pin used for the output flip-flop clock, OK.

When the multiplexer is configured as a 2-input function generator, logic can be implemented within the IOB itself. Combined with a Global buffer, this arrangement allows very high-speed gating of a single signal. For example, a wide decoder can be implemented in CLBs, and its output gated with a Read or Write Strobe driven by a global buffer.

The user can specify that the IOB function generator be used by placing special library symbols beginning with the letter "O." For example, a 2-input AND gate in the IOB function generator is called OAND2. Use the symbol input pin labeled "F" for the signal on the critical path. This signal is placed on the OK pin — the IOB input with the shortest delay to the function generator. Two examples are shown in Figure 7.



Figure 7: AND and MUX Symbols in Spartan-XL IOB

### Output Buffer

An active High 3-state signal can be used to place the output buffer in a high-impedance state, implementing 3-state outputs or bidirectional I/O. Under configuration control, the output (O) and output 3-state (T) signals can be inverted. The polarity of these signals is independently configured for each IOB (see Figure 6, page 7). An output can be configured as open-drain (open-collector) by tying the 3-state pin (T) to the output signal, and the input pin (I) to Ground.

By default, a 5V Spartan device output buffer pull-up structure is configured as a TTL-like totem-pole. The High driver is an n-channel pull-up transistor, pulling to a voltage one transistor threshold below  $V_{CC}$ . Alternatively, the outputs can be globally configured as CMOS drivers, with additional p-channel pull-up transistors pulling to  $V_{CC}$ . This option, applied using the bitstream generation software, applies to all outputs on the device. It is not individually programmable.

All Spartan-XL device outputs are configured as CMOS drivers, therefore driving rail-to-rail. The Spartan-XL family outputs are individually programmable for 12 mA or 24 mA output drive.

Any 5V Spartan device with its outputs configured in TTL mode can drive the inputs of any typical 3.3V device. Supported destinations for Spartan/XL device outputs are shown in Table 7.

### Three-State Register (Spartan-XL Family Only)

Spartan-XL devices incorporate an optional register controlling the three-state enable in the IOBs. The use of the three-state control register can significantly improve output enable and disable time.

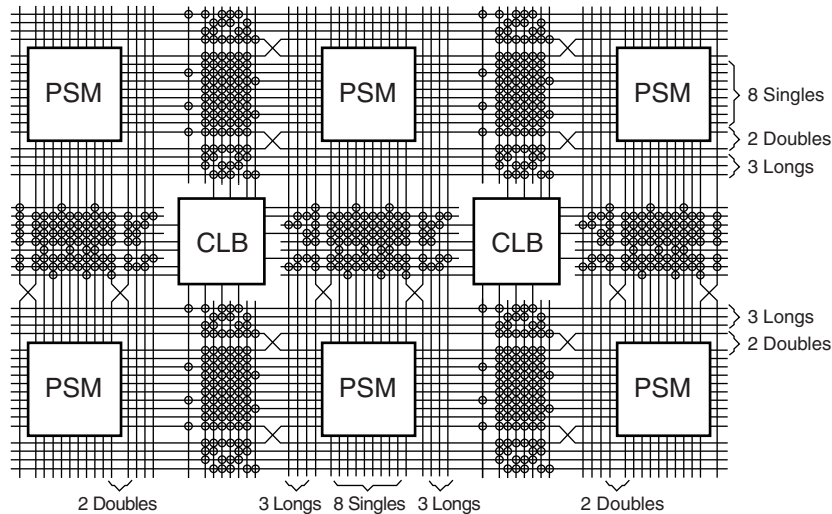
### Output Slew Rate

The slew rate of each output buffer is, by default, reduced, to minimize power bus transients when switching non-critical signals. For critical signals, attach a FAST attribute or property to the output buffer or flip-flop.

Spartan/XL devices have a feature called "Soft Start-up," designed to reduce ground bounce when all outputs are turned on simultaneously at the end of configuration. When the configuration process is finished and the device starts up, the first activation of the outputs is automatically slew-rate limited. Immediately following the initial activation of the I/O, the slew rate of the individual outputs is determined by the individual configuration option for each IOB.

### Pull-up and Pull-down Network

Programmable pull-up and pull-down resistors are used for tying unused pins to  $V_{CC}$  or Ground to minimize power consumption and reduce noise sensitivity. The configurable pull-up resistor is a p-channel transistor that pulls to  $V_{CC}$ . The configurable pull-down resistor is an n-channel transistor that pulls to Ground. The value of these resistors is typically 20 K $\Omega$  – 100 K $\Omega$  (See "Spartan Family DC Characteristics Over Operating Conditions" on page 43.).

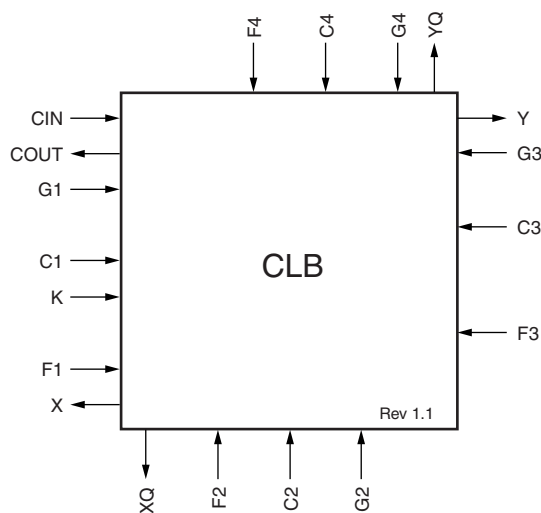


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Figure 8: Spartan/XL CLB Routing Channels and Interface Block Diagram

### CLB Interface

A block diagram of the CLB interface signals is shown in Figure 9. The input signals to the CLB are distributed evenly on all four sides providing maximum routing flexibility. In general, the entire architecture is symmetrical and regular. It is well suited to established placement and routing algorithms. Inputs, outputs, and function generators can freely swap positions within a CLB to avoid routing congestion during the placement and routing operation. The exceptions are the clock (K) input and CIN/COUT signals. The K input is routed to dedicated global vertical lines as well as four single-length lines and is on the left side of the CLB. The CIN/COUT signals are routed through dedicated interconnects which do not interfere with the general routing structure. The output signals from the CLB are available to drive both vertical and horizontal channels.



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Figure 9: CLB Interconnect Signals

### Programmable Switch Matrices

The horizontal and vertical single- and double-length lines intersect at a box called a programmable switch matrix (PSM). Each PSM consists of programmable pass transistors used to establish connections between the lines (see Figure 10).

For example, a single-length signal entering on the right side of the switch matrix can be routed to a single-length line on the top, left, or bottom sides, or any combination thereof, if multiple branches are required. Similarly, a double-length signal can be routed to a double-length line on any or all of the other three edges of the programmable switch matrix.

### Single-Length Lines

Single-length lines provide the greatest interconnect flexibility and offer fast routing between adjacent blocks. There are eight vertical and eight horizontal single-length lines associated with each CLB. These lines connect the switching matrices that are located in every row and column of CLBs. Single-length lines are connected by way of the programmable switch matrices, as shown in Figure 10. Routing connectivity is shown in Figure 8.

Single-length lines incur a delay whenever they go through a PSM. Therefore, they are not suitable for routing signals for long distances. They are normally used to conduct signals within a localized area and to provide the branching for nets with fanout greater than one.

- The 16 x 1 single-port configuration contains a RAM array with 16 locations, each one-bit wide. One 4-bit address decoder determines the RAM location for write and read operations. There is one input for writing data and one output for reading data, all at the selected address.
- The (16 x 1) x 2 single-port configuration combines two 16 x 1 single-port configurations (each according to the preceding description). There is one data input, one data output and one address decoder for each array. These arrays can be addressed independently.
- The 32 x 1 single-port configuration contains a RAM array with 32 locations, each one-bit wide. There is one data input, one data output, and one 5-bit address decoder.
- The dual-port mode 16 x 1 configuration contains a RAM array with 16 locations, each one-bit wide. There are two 4-bit address decoders, one for each port. One port consists of an input for writing and an output for reading, all at a selected address. The other port consists of one output for reading from an independently selected address.

The appropriate choice of RAM configuration mode for a given design should be based on timing and resource requirements, desired functionality, and the simplicity of the design process. Selection criteria include the following: Whereas the 32 x 1 single-port, the (16 x 1) x 2 single-port, and the 16 x 1 dual-port configurations each use one entire CLB, the 16 x 1 single-port configuration uses only one half of a CLB. Due to its simultaneous read/write capability, the dual-port RAM can transfer twice as much data as the single-port RAM, which permits only one data operation at any given time.

CLB memory configuration options are selected by using the appropriate library symbol in the design entry.

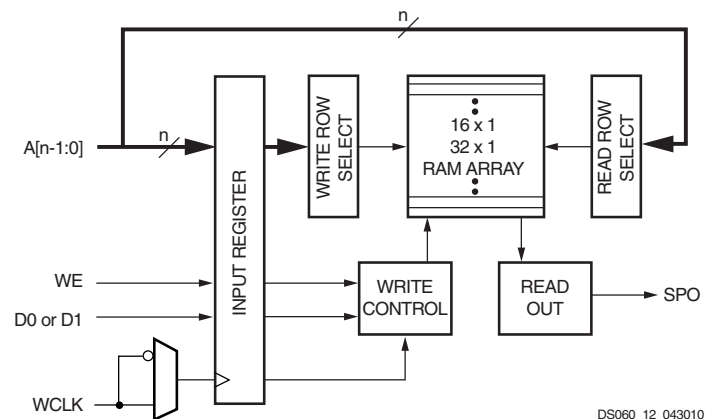
### Single-Port Mode

There are three CLB memory configurations for the single-port RAM: 16 x 1, (16 x 1) x 2, and 32 x 1, the functional organization of which is shown in [Figure 12](#).

The single-port RAM signals and the CLB signals ([Figure 2](#), [page 4](#)) from which they are originally derived are shown in [Table 9](#).

**Table 9: Single-Port RAM Signals**

RAM Signal	Function	CLB Signal
D0 or D1	Data In	DIN or H1
A[3:0]	Address	F[4:1] or G[4:1]
A4 (32 x 1 only)	Address	H1
WE	Write Enable	SR
WCLK	Clock	K
SPO	Single Port Out (Data Out)	F <sub>OUT</sub> or G <sub>OUT</sub>



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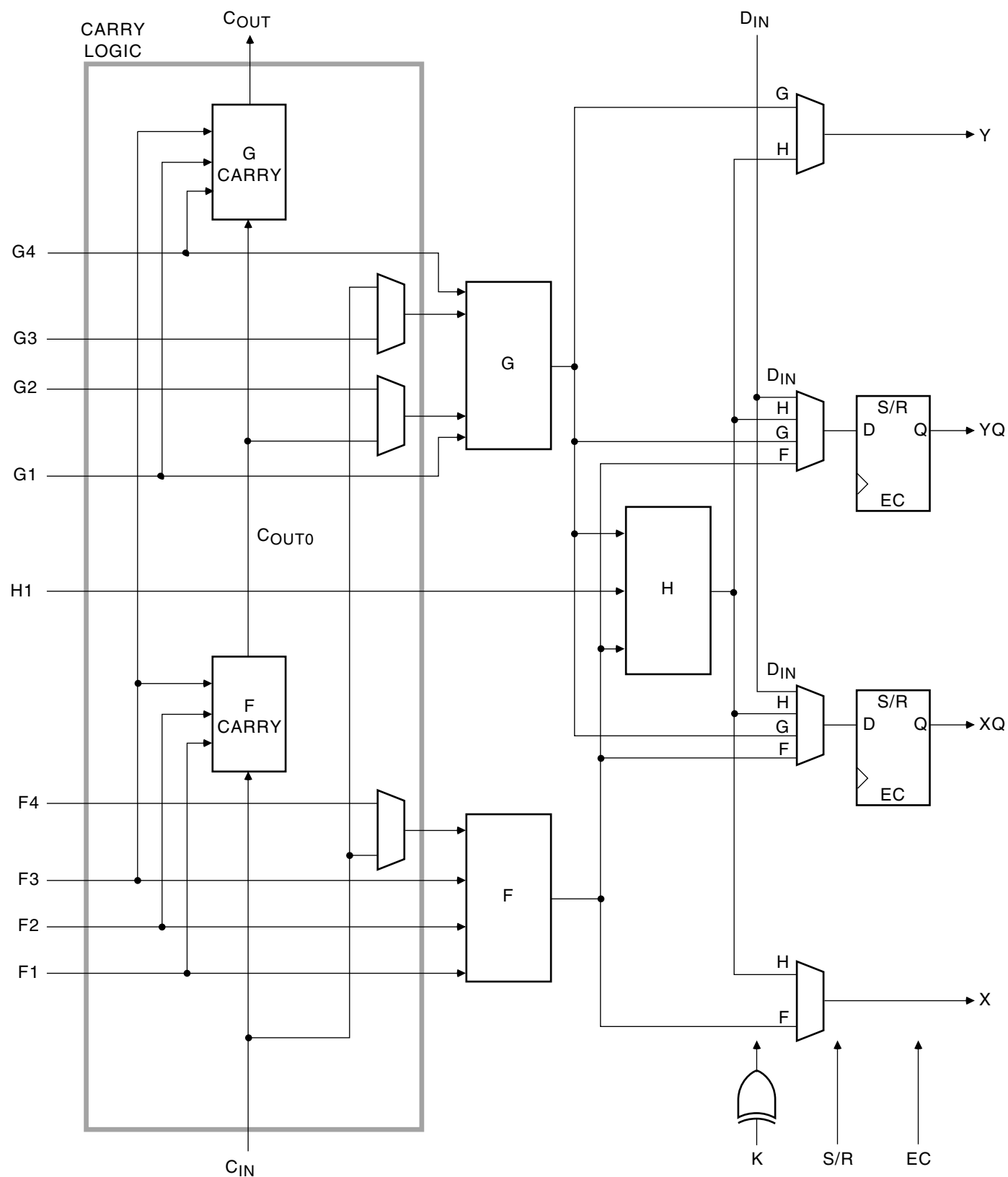
### Notes:

1. The (16 x 1) x 2 configuration combines two 16 x 1 single-port RAMs, each with its own independent address bus and data input. The same WE and WCLK signals are connected to both RAMs.
2.  $n = 4$  for the 16 x 1 and (16 x 1) x 2 configurations.  $n = 5$  for the 32 x 1 configuration.

**Figure 12: Logic Diagram for the Single-Port RAM**

Writing data to the single-port RAM is essentially the same as writing to a data register. It is an edge-triggered (synchronous) operation performed by applying an address to the A inputs and data to the D input during the active edge of WCLK while WE is High.

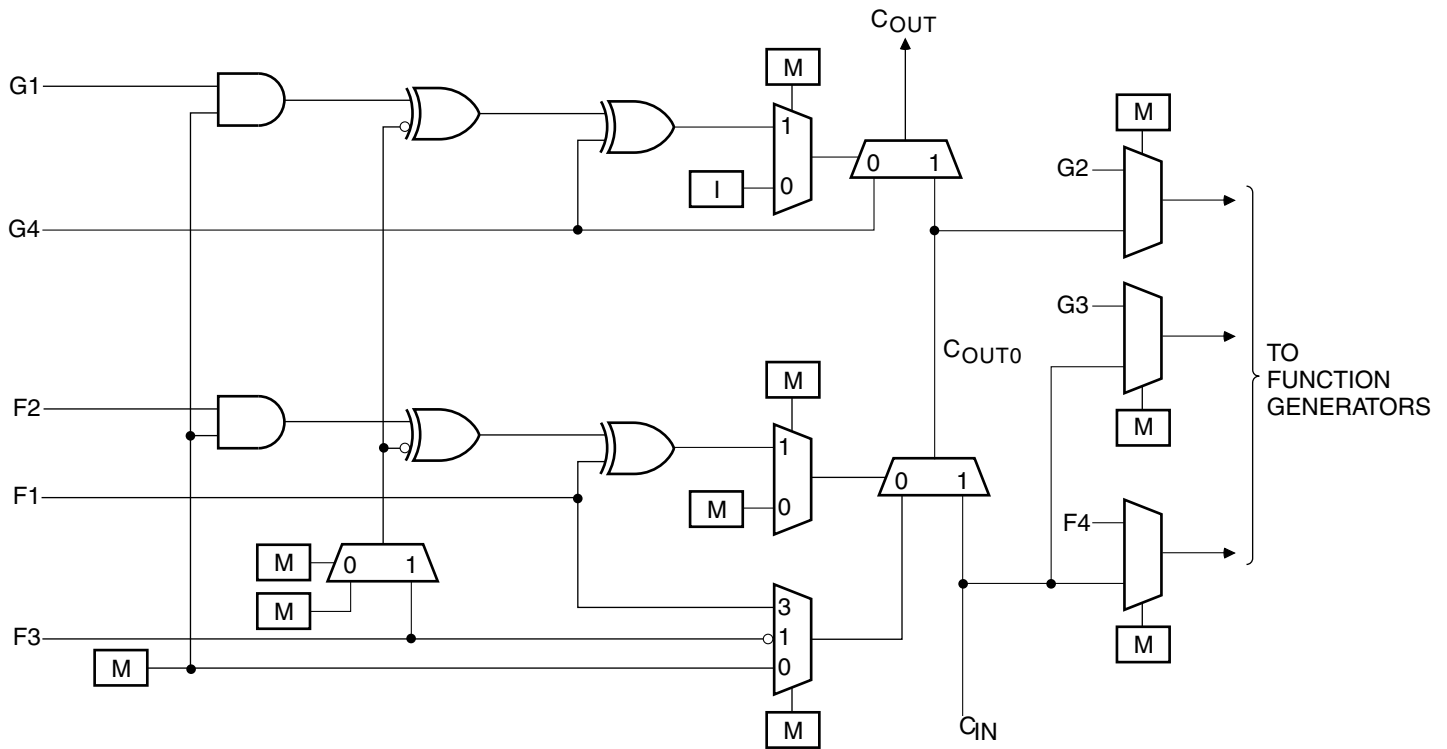
The timing relationships are shown in [Figure 13](#). The High logic level on WE enables the input data register for writing. The active edge of WCLK latches the address, input data, and WE signals. Then, an internal write pulse is generated that loads the data into the memory cell.



**Figure 16: Fast Carry Logic in Spartan/XL CLB**

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Figure 17: Detail of Spartan/XL Dedicated Carry Logic

### 3-State Long Line Drivers

A pair of 3-state buffers is associated with each CLB in the array. These 3-state buffers (BUFT) can be used to drive signals onto the nearest horizontal longlines above and below the CLB. They can therefore be used to implement multiplexed or bidirectional buses on the horizontal longlines, saving logic resources.

There is a weak keeper at each end of these two horizontal longlines. This circuit prevents undefined floating levels. However, it is overridden by any driver.

The buffer enable is an active High 3-state (i.e., an active Low enable), as shown in Table 11.

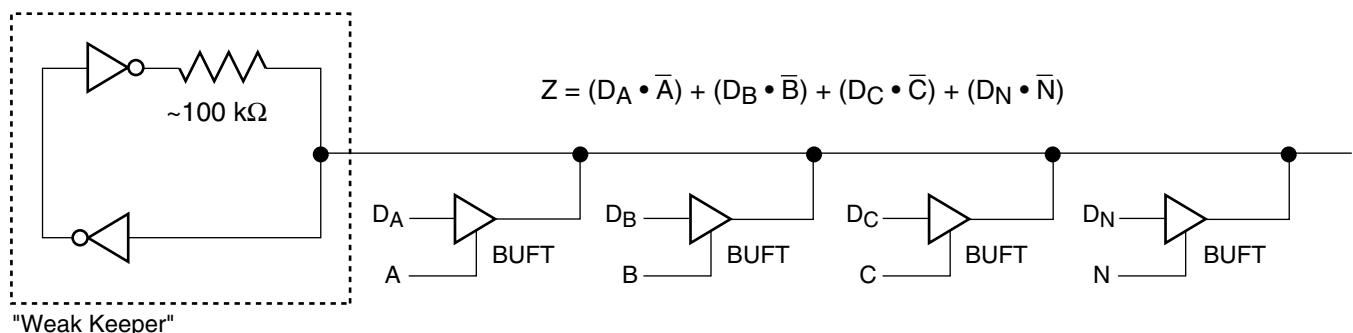
### Three-State Buffer Example

Figure 18 shows how to use the 3-state buffers to implement a multiplexer. The selection is accomplished by the buffer 3-state signal.

Pay particular attention to the polarity of the T pin when using these buffers in a design. Active High 3-state (T) is identical to an active Low output enable, as shown in Table 11.

Table 11: Three-State Buffer Functionality

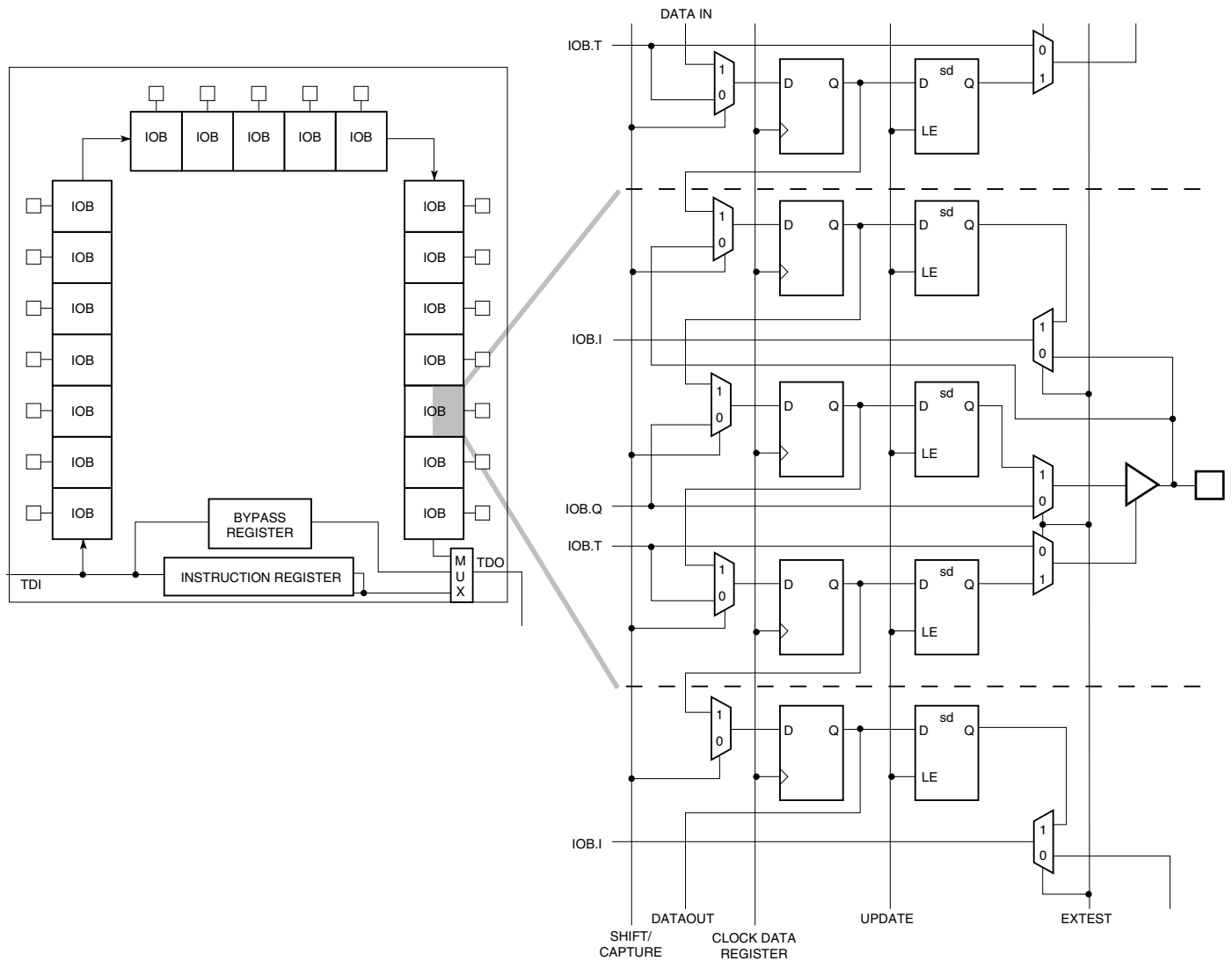
IN	T	OUT
X	1	Z
IN	0	IN



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Figure 18: 3-state Buffers Implement a Multiplexer





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Figure 20: Spartan/XL Boundary Scan Logic

figuration are shown in Table 14 and Table 15.

**Table 14: Pin Functions During Configuration (Spartan Family Only)**

Configuration Mode (MODE Pin)		User Operation
Slave Serial (High)	Master Serial (Low)	
MODE (I)	MODE (I)	MODE
HDC (High)	HDC (High)	I/O
$\overline{\text{LDC}}$ (Low)	$\overline{\text{LDC}}$ (Low)	I/O
$\overline{\text{INIT}}$	$\overline{\text{INIT}}$	I/O
DONE	DONE	DONE
$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$
CCLK (I)	CCLK (O)	CCLK (I)
DIN (I)	DIN (I)	I/O
DOUT	DOUT	SGCK4-I/O
TDI	TDI	TDI-I/O
TCK	TCK	TCK-I/O
TMS	TMS	TMS-I/O
TDO	TDO	TDO-(O)
		ALL OTHERS

**Notes:**

1. A shaded table cell represents the internal pull-up used before and during configuration.
2. (I) represents an input; (O) represents an output.
3.  $\overline{\text{INIT}}$  is an open-drain output during configuration.

**Table 15: Pin Functions During Configuration (Spartan-XL Family Only)**

CONFIGURATION MODE <M1:M0>			User Operation
Slave Serial [1:1]	Master Serial [1:0]	Express [0:X]	
M1 (High) (I)	M1 (High) (I)	M1(Low) (I)	M1
M0 (High) (I)	M0 (Low) (I)	M0 (I)	M0
HDC (High)	HDC (High)	HDC (High)	I/O
$\overline{\text{LDC}}$ (Low)	$\overline{\text{LDC}}$ (Low)	$\overline{\text{LDC}}$ (Low)	I/O
$\overline{\text{INIT}}$	$\overline{\text{INIT}}$	$\overline{\text{INIT}}$	I/O
DONE	DONE	DONE	DONE
$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$
CCLK (I)	CCLK (O)	CCLK (I)	CCLK (I)
		DATA 7 (I)	I/O
		DATA 6 (I)	I/O
		DATA 5 (I)	I/O
		DATA 4 (I)	I/O
		DATA 3 (I)	I/O
		DATA 2 (I)	I/O
		DATA 1 (I)	I/O
DIN (I)	DIN (I)	DATA 0 (I)	I/O
DOUT	DOUT	DOUT	GCK6-I/O
TDI	TDI	TDI	TDI-I/O
TCK	TCK	TCK	TCK-I/O
TMS	TMS	TMS	TMS-I/O
TDO	TDO	TDO	TDO-(O)
		CS1	I/O
			ALL OTHERS

**Notes:**

1. A shaded table cell represents the internal pull-up used before and during configuration.
2. (I) represents an input; (O) represents an output.
3.  $\overline{\text{INIT}}$  is an open-drain output during configuration.

to wait after completing the configuration memory clear operation. When  $\overline{\text{INIT}}$  is no longer held Low externally, the device determines its configuration mode by capturing the state of the Mode pins, and is ready to start the configuration process. A master device waits up to an additional 300  $\mu\text{s}$  to make sure that any slaves in the optional daisy chain have seen that  $\overline{\text{INIT}}$  is High.

For more details on Configuration, refer to the Xilinx Application Note "FPGA Configuration Guidelines" (XAPP090).

### Start-Up

Start-up is the transition from the configuration process to the intended user operation. This transition involves a change from one clock source to another, and a change from interfacing parallel or serial configuration data where most outputs are 3-stated, to normal operation with I/O pins active in the user system. Start-up must make sure that the user logic 'wakes up' gracefully, that the outputs become active without causing contention with the configuration signals, and that the internal flip-flops are released from the Global Set/Reset (GSR) at the right time.

#### Start-Up Initiation

Two conditions have to be met in order for the start-up sequence to begin:

- The chip's internal memory must be full, and
- The configuration length count must be met, exactly.

In all configuration modes except Express mode, Spartan/XL devices read the expected length count from the bitstream and store it in an internal register. The length count varies according to the number of devices and the composition of the daisy chain. Each device also counts the number of CCLKs during configuration.

In Express mode, there is no length count. The start-up sequence for each device begins when the device has received its quota of configuration data. Wiring the DONE pins of several devices together delays start-up of all devices until all are fully configured.

#### Start-Up Events

The device can be programmed to control three start-up events.

- The release of the open-drain DONE output
- The termination of the Global Three-State and the change of configuration-related pins to the user function, activating all IOBs.
- The termination of the Global Set/Reset initialization of all CLB and IOB storage elements.

Figure 31 describes start-up timing in detail. The three events — DONE going High, the internal GSR being de-activated, and the user I/O going active — can all occur in any arbitrary sequence. This relative timing is selected by options in the bitstream generation software. Heavy lines in Figure 31 show the default timing. The thin lines indicate all other possible timing options. The start-up logic must be clocked until the "F" (Finished) state is reached.

The default option, and the most practical one, is for DONE to go High first, disconnecting the configuration data source and avoiding any contention when the I/Os become active one clock later. GSR is then released another clock period later to make sure that user operation starts from stable internal conditions. This is the most common sequence, shown with heavy lines in Figure 31, but the designer can modify it to meet particular requirements.

#### Start-Up Clock

Normally, the start-up sequence is controlled by the internal device oscillator (CCLK), which is asynchronous to the system clock. As a configuration option, they can be triggered by an on-chip user net called UCLK. This user net can be accessed by placing the STARTUP library symbol, and the start-up modes are known as UCLK\_NOSYNC or UCLK\_SYNC. This allows the device to wake up in synchronism with the user system.

#### DONE Pin

Note that DONE is an open-drain output and does not go High unless an internal pull-up is activated or an external pull-up is attached. The internal pull-up is activated as the default by the bitstream generation software.

The DONE pin can also be wire-ANDed with DONE pins of other FPGAs or with other external signals, and can then be used as input to the start-up control logic. This is called "Start-up Timing Synchronous to Done In" and is selected by either CCLK\_SYNC or UCLK\_SYNC. When DONE is not used as an input, the operation is called "Start-up Timing Not Synchronous to DONE In," and is selected by either CCLK\_NOSYNC or UCLK\_NOSYNC. Express mode configuration always uses either CCLK\_SYNC or UCLK\_SYNC timing, while the other configuration modes can use any of the four timing sequences.

When the UCLK\_SYNC option is enabled, the user can externally hold the open-drain DONE output Low, and thus stall all further progress in the start-up sequence until DONE is released and has gone High. This option can be used to force synchronization of several FPGAs to a common user clock, or to guarantee that all devices are successfully configured before any I/Os go active.

## Readback

The user can read back the content of configuration memory and the level of certain internal nodes without interfering with the normal operation of the device.

Readback not only reports the downloaded configuration bits, but can also include the present state of the device, represented by the content of all flip-flops and latches in CLBs and IOBs, as well as the content of function generators used as RAMs.

Although readback can be performed while the device is operating, for best results and to freeze a known capture state, it is recommended that the clock inputs be stopped until readback is complete.

Readback of Spartan-XL family Express mode bitstreams results in data that does not resemble the original bitstream, because the bitstream format differs from other modes.

Spartan/XL FPGA Readback does not use any dedicated pins, but uses four internal nets (RDBK.TRIG, RDBK.DATA, RDBK.RIP and RDBK.CLK) that can be routed to any IOB. To access the internal Readback signals, instantiate the READBACK library symbol and attach the appropriate pad symbols, as shown in **Figure 32**.

After Readback has been initiated by a Low-to-High transition on RDBK.TRIG, the RDBK.RIP (Read In Progress) output goes High on the next rising edge of RDBK.CLK. Subsequent rising edges of this clock shift out Readback data on the RDBK.DATA net.

Readback data does not include the preamble, but starts with five dummy bits (all High) followed by the Start bit (Low)

of the first frame. The first two data bits of the first frame are always High.

Each frame ends with four error check bits. They are read back as High. The last seven bits of the last frame are also read back as High. An additional Start bit (Low) and an 11-bit Cyclic Redundancy Check (CRC) signature follow, before RDBK.RIP returns Low.

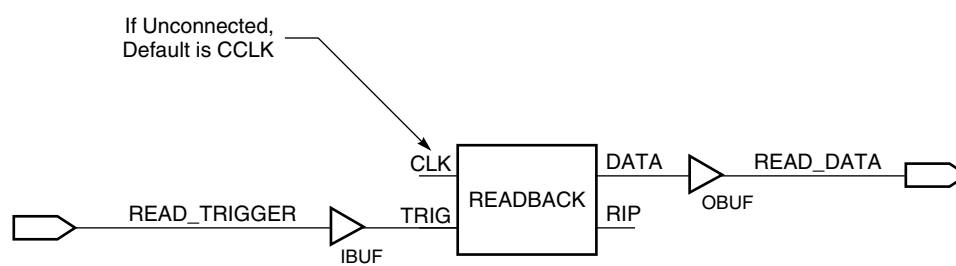
## Readback Options

Readback options are: Readback Capture, Readback Abort, and Clock Select. They are set with the bitstream generation software.

## Readback Capture

When the Readback Capture option is selected, the data stream includes sampled values of CLB and IOB signals. The rising edge of RDBK.TRIG latches the inverted values of the four CLB outputs, the IOB output flip-flops and the input signals I1 and I2. Note that while the bits describing configuration (interconnect, function generators, and RAM content) are *not* inverted, the CLB and IOB output signals *are* inverted. RDBK.TRIG is located in the lower-left corner of the device.

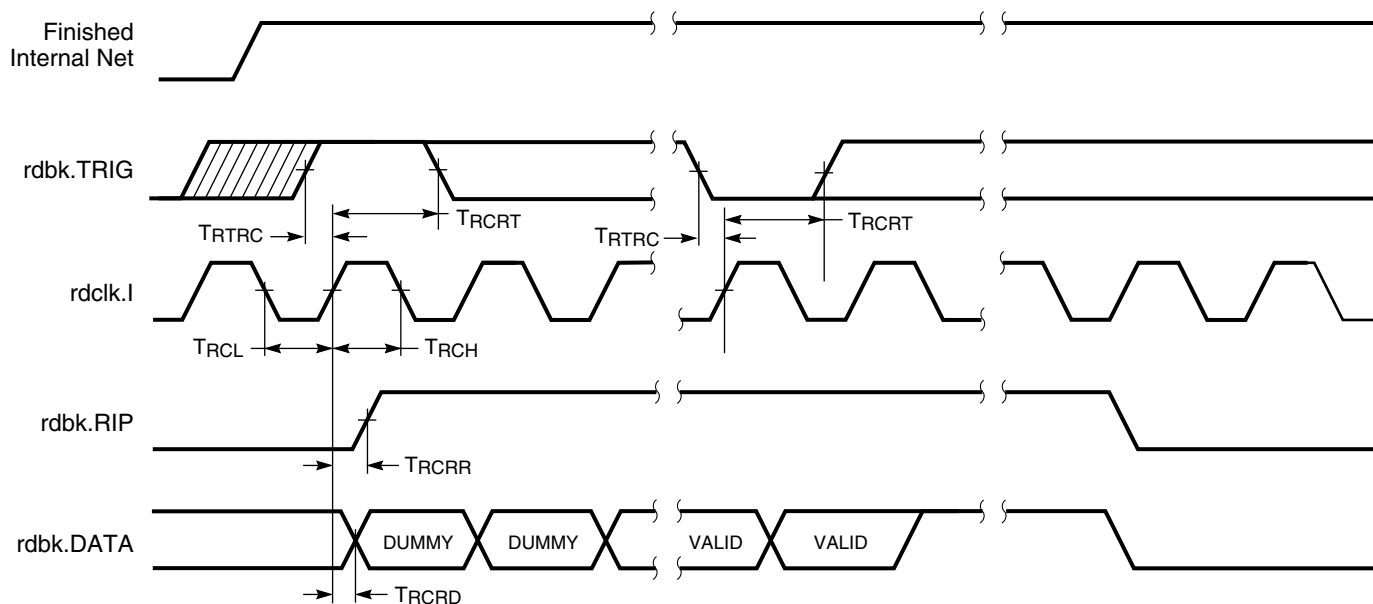
When the Readback Capture option is not selected, the values of the capture bits reflect the configuration data originally written to those memory locations. If the RAM capability of the CLBs is used, RAM data are available in Readback, since they directly overwrite the F and G function-table configuration of the CLB.



**Figure 32: Readback Example**

## Readback Switching Characteristics Guidelines

The following guidelines reflect worst-case values over the recommended operating conditions.



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Figure 33: Spartan and Spartan-XL Readback Timing Diagram

### Spartan and Spartan-XL Readback Switching Characteristics

Symbol		Description	Min	Max	Units
$T_{RTRC}$	rdbk.TRIG	rdbk.TRIG setup to initiate and abort Readback	200	-	ns
$T_{RCRT}$		rdbk.TRIG hold to initiate and abort Readback	50	-	ns
$T_{RCRD}$	rdclk.I	rdbk.DATA delay	-	250	ns
$T_{RCRR}$		rdbk.RIP delay	-	250	ns
$T_{RCH}$		High time	250	500	ns
$T_{RCL}$		Low time	250	500	ns

#### Notes:

1. Timing parameters apply to all speed grades.
2. If rdbk.TRIG is High prior to Finished, Finished will trigger the first Readback.

## Spartan Family Detailed Specifications

### Definition of Terms

In the following tables, some specifications may be designated as Advance or Preliminary. These terms are defined as follows:

**Advance:** Initial estimates based on simulation and/or extrapolation from other speed grades, devices, or families. Values are subject to change. Use as estimates, not for production.

**Preliminary:** Based on preliminary characterization. Further changes are not expected.

**Unmarked:** Specifications not identified as either Advance or Preliminary are to be considered Final.

Notwithstanding the definition of the above terms, all specifications are subject to change without notice.

Except for pin-to-pin input and output parameters, the AC parameter delay specifications included in this document are derived from measuring internal test patterns. All specifications are representative of worst-case supply voltage and junction temperature conditions. The parameters included are common to popular designs and typical applications.

### Spartan Family Absolute Maximum Ratings<sup>(1)</sup>

Symbol	Description		Value	Units
$V_{CC}$	Supply voltage relative to GND		−0.5 to +7.0	V
$V_{IN}$	Input voltage relative to GND <sup>(2,3)</sup>		−0.5 to $V_{CC} + 0.5$	V
$V_{TS}$	Voltage applied to 3-state output <sup>(2,3)</sup>		−0.5 to $V_{CC} + 0.5$	V
$T_{STG}$	Storage temperature (ambient)		−65 to +150	°C
$T_J$	Junction temperature	Plastic packages	+125	°C

#### Notes:

- Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.
- Maximum DC overshoot (above  $V_{CC}$ ) or undershoot (below GND) must be limited to either 0.5V or 10 mA, whichever is easier to achieve.
- Maximum AC (during transitions) conditions are as follows; the device pins may undershoot to −2.0V or overshoot to +7.0V, provided this overshoot or undershoot lasts no more than 11 ns with a forcing current no greater than 100 mA.
- For soldering guidelines, see the Package Information on the Xilinx website.

### Spartan Family Recommended Operating Conditions

Symbol	Description		Min	Max	Units
$V_{CC}$	Supply voltage relative to GND, $T_J = 0^{\circ}\text{C}$ to $+85^{\circ}\text{C}$	Commercial	4.75	5.25	V
	Supply voltage relative to GND, $T_J = -40^{\circ}\text{C}$ to $+100^{\circ}\text{C}$ <sup>(1)</sup>	Industrial	4.5	5.5	V
$V_{IH}$	High-level input voltage <sup>(2)</sup>	TTL inputs	2.0	$V_{CC}$	V
		CMOS inputs	70%	100%	$V_{CC}$
$V_{IL}$	Low-level input voltage <sup>(2)</sup>	TTL inputs	0	0.8	V
		CMOS inputs	0	20%	$V_{CC}$
$T_{IN}$	Input signal transition time		-	250	ns

#### Notes:

- At junction temperatures above those listed as Recommended Operating Conditions, all delay parameters increase by 0.35% per °C.
- Input and output measurement thresholds are: 1.5V for TTL and 2.5V for CMOS.

### Spartan Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan devices and are expressed in nanoseconds unless otherwise noted.

Symbol	Single Port RAM	Size <sup>(1)</sup>	Speed Grade				Units
			-4		-3		
			Min	Max	Min	Max	
Write Operation							
T <sub>WCS</sub>	Address write cycle time (clock K period)	16x2	8.0	-	11.6	-	ns
T <sub>WCTS</sub>		32x1	8.0	-	11.6	-	ns
T <sub>WPS</sub>	Clock K pulse width (active edge)	16x2	4.0	-	5.8	-	ns
T <sub>WPTS</sub>		32x1	4.0	-	5.8	-	ns
T <sub>ASS</sub>	Address setup time before clock K	16x2	1.5	-	2.0	-	ns
T <sub>ASTS</sub>		32x1	1.5	-	2.0	-	ns
T <sub>AHS</sub>	Address hold time after clock K	16x2	0.0	-	0.0	-	ns
T <sub>AHTS</sub>		32x1	0.0	-	0.0	-	ns
T <sub>DSS</sub>	DIN setup time before clock K	16x2	1.5	-	2.7	-	ns
T <sub>DSTS</sub>		32x1	1.5	-	1.7	-	ns
T <sub>DHS</sub>	DIN hold time after clock K	16x2	0.0	-	0.0	-	ns
T <sub>DHTS</sub>		32x1	0.0	-	0.0	-	ns
T <sub>WSS</sub>	WE setup time before clock K	16x2	1.5	-	1.6	-	ns
T <sub>WSTS</sub>		32x1	1.5	-	1.6	-	ns
T <sub>WHS</sub>	WE hold time after clock K	16x2	0.0	-	0.0	-	ns
T <sub>WHTS</sub>		32x1	0.0	-	0.0	-	ns
T <sub>WOS</sub>	Data valid after clock K	16x2	-	6.5	-	7.9	ns
T <sub>WOTS</sub>		32x1	-	7.0	-	9.3	ns
Read Operation							
T <sub>RC</sub>	Address read cycle time	16x2	2.6	-	2.6	-	ns
T <sub>RCT</sub>		32x1	3.8	-	3.8	-	ns
T <sub>ILO</sub>	Data valid after address change (no Write Enable)	16x2	-	1.2	-	1.6	ns
T <sub>IHO</sub>		32x1	-	2.0	-	2.7	ns
T <sub>ICK</sub>	Address setup time before clock K	16x2	1.8	-	2.4	-	ns
T <sub>IHCK</sub>		32x1	2.9	-	3.9	-	ns

#### Notes:

1. Timing for 16 x 1 RAM option is identical to 16 x 2 RAM timing.



### Spartan Family Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case operating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading.

ating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading.

#### Spartan Family Primary and Secondary Setup and Hold

Symbol	Description	Device	Speed Grade		Units
			-4	-3	
			Min	Min	
Input Setup/Hold Times Using Primary Clock and IFF					
T <sub>PSUF</sub> /T <sub>PHF</sub>	No Delay	XCS05	1.2 / 1.7	1.8 / 2.5	ns
		XCS10	1.0 / 2.3	1.5 / 3.4	ns
		XCS20	0.8 / 2.7	1.2 / 4.0	ns
		XCS30	0.6 / 3.0	0.9 / 4.5	ns
		XCS40	0.4 / 3.5	0.6 / 5.2	ns
T <sub>PSU</sub> /T <sub>PH</sub>	With Delay	XCS05	4.3 / 0.0	6.0 / 0.0	ns
		XCS10	4.3 / 0.0	6.0 / 0.0	ns
		XCS20	4.3 / 0.0	6.0 / 0.0	ns
		XCS30	4.3 / 0.0	6.0 / 0.0	ns
		XCS40	5.3 / 0.0	6.8 / 0.0	ns
Input Setup/Hold Times Using Secondary Clock and IFF					
T <sub>SSUF</sub> /T <sub>SHF</sub>	No Delay	XCS05	0.9 / 2.2	1.5 / 3.0	ns
		XCS10	0.7 / 2.8	1.2 / 3.9	ns
		XCS20	0.5 / 3.2	0.9 / 4.5	ns
		XCS30	0.3 / 3.5	0.6 / 5.0	ns
		XCS40	0.1 / 4.0	0.3 / 5.7	ns
T <sub>SSU</sub> /T <sub>SH</sub>	With Delay	XCS05	4.0 / 0.0	5.7 / 0.0	ns
		XCS10	4.0 / 0.0	5.7 / 0.0	ns
		XCS20	4.0 / 0.5	5.7 / 0.5	ns
		XCS30	4.0 / 0.5	5.7 / 0.5	ns
		XCS40	5.0 / 0.0	6.5 / 0.0	ns

#### Notes:

1. Setup time is measured with the fastest route and the lightest load. Hold time is measured using the furthest distance and a reference load of one clock pin per IOB/CLB.
2. IFF = Input Flip-flop or Latch

## Spartan-XL Family IOB Input Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol		Device	Speed Grade				Units
			-5		-4		
	Description		Min	Max	Min	Max	
Setup Times							
T <sub>ECIK</sub>	Clock Enable (EC) to Clock (IK)	All devices	0.0	-	0.0	-	ns
T <sub>PICK</sub>	Pad to Clock (IK), no delay	All devices	1.0	-	1.2	-	ns
T <sub>POCK</sub>	Pad to Fast Capture Latch Enable (OK), no delay	All devices	0.7	-	0.8	-	ns
Hold Times							
	All Hold Times	All devices	0.0	-	0.0	-	ns
Propagation Delays							
T <sub>PID</sub>	Pad to I1, I2	All devices	-	0.9	-	1.1	ns
T <sub>PLI</sub>	Pad to I1, I2 via transparent input latch, no delay	All devices	-	2.1	-	2.5	ns
T <sub>IKRI</sub>	Clock (IK) to I1, I2 (flip-flop)	All devices	-	1.0	-	1.1	ns
T <sub>IKLI</sub>	Clock (IK) to I1, I2 (latch enable, active Low)	All devices	-	1.1	-	1.2	ns
Delay Adder for Input with Full Delay Option							
T <sub>Delay</sub>	T <sub>PICKD</sub> = T <sub>PICK</sub> + T <sub>Delay</sub> T <sub>PDLI</sub> = T <sub>PLI</sub> + T <sub>Delay</sub>	XCS05XL	4.0	-	4.7	-	ns
		XCS10XL	4.8	-	5.6	-	ns
		XCS20XL	5.0	-	5.9	-	ns
		XCS30XL	5.5	-	6.5	-	ns
		XCS40XL	6.5	-	7.6	-	ns
Global Set/Reset							
T <sub>MRW</sub>	Minimum GSR pulse width	All devices	10.5	-	11.5	-	ns
T <sub>RRI</sub>	Delay from GSR input to any Q	XCS05XL	-	9.0	-	10.5	ns
		XCS10XL	-	9.5	-	11.0	ns
		XCS20XL	-	10.0	-	11.5	ns
		XCS30XL	-	11.0	-	12.5	ns
		XCS40XL	-	12.0	-	13.5	ns

### Notes:

- Input pad setup and hold times are specified with respect to the internal clock (IK). For setup and hold times with respect to the clock input, see the pin-to-pin parameters in the Pin-to-Pin Input Parameters table.
- Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

### Spartan-XL Family IOB Output Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to

the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values are expressed in nanoseconds unless otherwise noted.

Symbol	Description	Device	Speed Grade				Units
			-5		-4		
			Min	Max	Min	Max	
Propagation Delays							
T <sub>OKPOF</sub>	Clock (OK) to Pad, fast	All devices	-	3.2	-	3.7	ns
T <sub>OPF</sub>	Output (O) to Pad, fast	All devices	-	2.5	-	2.9	ns
T <sub>TSHZ</sub>	3-state to Pad High-Z (slew-rate independent)	All devices	-	2.8	-	3.3	ns
T <sub>TSONF</sub>	3-state to Pad active and valid, fast	All devices	-	2.6	-	3.0	ns
T <sub>OFFPF</sub>	Output (O) to Pad via Output MUX, fast	All devices	-	3.7	-	4.4	ns
T <sub>OKFPF</sub>	Select (OK) to Pad via Output MUX, fast	All devices	-	3.3	-	3.9	ns
T <sub>SLOW</sub>	For Output SLOW option add	All devices	-	1.5	-	1.7	ns
Setup and Hold Times							
T <sub>OOK</sub>	Output (O) to clock (OK) setup time	All devices	0.5	-	0.5	-	ns
T <sub>OKO</sub>	Output (O) to clock (OK) hold time	All devices	0.0	-	0.0	-	ns
T <sub>ECOK</sub>	Clock Enable (EC) to clock (OK) setup time	All devices	0.0	-	0.0	-	ns
T <sub>OKEC</sub>	Clock Enable (EC) to clock (OK) hold time	All devices	0.1	-	0.2	-	ns
Global Set/Reset							
T <sub>MRW</sub>	Minimum GSR pulse width	All devices	10.5	-	11.5	-	ns
T <sub>RPO</sub>	Delay from GSR input to any Pad	XCS05XL	-	11.9	-	14.0	ns
		XCS10XL	-	12.4	-	14.5	ns
		XCS20XL	-	12.9	-	15.0	ns
		XCS30XL	-	13.9	-	16.0	ns
		XCS40XL	-	14.9	-	17.0	ns

#### Notes:

- Output timing is measured at ~50%  $V_{CC}$  threshold, with 50 pF external capacitive loads including test fixture. Slew-rate limited output rise/fall times are approximately two times longer than fast output rise/fall times.
- Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

## Pin Descriptions

There are three types of pins in the Spartan/XL devices:

- Permanently dedicated pins
- User I/O pins that can have special functions
- Unrestricted user-programmable I/O pins.

Before and during configuration, all outputs not used for the configuration process are 3-stated with the I/O pull-up resistor network activated. After configuration, if an IOB is unused it is configured as an input with the I/O pull-up resistor network remaining activated.

Any user I/O can be configured to drive the Global Set/Reset net GSR or the global three-state net GTS. See **Global Signals: GSR and GTS**, page 20 for more information.

Device pins for Spartan/XL devices are described in **Table 18**.

Some Spartan-XL devices are available in Pb-free package options. The Pb-free package options have the same pin-outs as the standard package options.

Table 18: Pin Descriptions

Pin Name	I/O During Config.	I/O After Config.	Pin Description
<b>Permanently Dedicated Pins</b>			
V <sub>CC</sub>	X	X	Eight or more (depending on package) connections to the nominal +5V supply voltage (+3.3V for Spartan-XL devices). All must be connected, and each must be decoupled with a 0.01 – 0.1 $\mu$ F capacitor to Ground.
GND	X	X	Eight or more (depending on package type) connections to Ground. All must be connected.
CCLK	I or O	I	During configuration, Configuration Clock (CCLK) is an output in Master mode and is an input in Slave mode. After configuration, CCLK has a weak pull-up resistor and can be selected as the Readback Clock. There is no CCLK High or Low time restriction on Spartan/XL devices, except during Readback. See <b>Violating the Maximum High and Low Time Specification for the Readback Clock</b> , page 39 for an explanation of this exception.
DONE	I/O	O	DONE is a bidirectional signal with an optional internal pull-up resistor. As an open-drain output, it indicates the completion of the configuration process. As an input, a Low level on DONE can be configured to delay the global logic initialization and the enabling of outputs.  The optional pull-up resistor is selected as an option in the program that creates the configuration bitstream. The resistor is included by default.
$\overline{\text{PROGRAM}}$	I	I	$\overline{\text{PROGRAM}}$ is an active Low input that forces the FPGA to clear its configuration memory. It is used to initiate a configuration cycle. When $\overline{\text{PROGRAM}}$ goes High, the FPGA finishes the current clear cycle and executes another complete clear cycle, before it goes into a WAIT state and releases $\overline{\text{INIT}}$ .  The $\overline{\text{PROGRAM}}$ pin has a permanent weak pull-up, so it need not be externally pulled up to VCC.
MODE (Spartan) M0, M1 (Spartan-XL)	I	X	The Mode input(s) are sampled after $\overline{\text{INIT}}$ goes High to determine the configuration mode to be used.  During configuration, these pins have a weak pull-up resistor. For the most popular configuration mode, Slave Serial, the mode pins can be left unconnected. For Master Serial mode, connect the Mode/M0 pin directly to system ground.

## XCS05 and XCS05XL Device Pinouts

XCS05/XL Pad Name	PC84 <sup>(4)</sup>	VQ100	Bndry Scan
I/O	P70	P71	238 <sup>(3)</sup>
I/O (D0 <sup>(2)</sup> , DIN)	P71	P72	241 <sup>(3)</sup>
I/O, SGCK4 <sup>(1)</sup> , GCK6 <sup>(2)</sup> (DOUT)	P72	P73	244 <sup>(3)</sup>
CCLK	P73	P74	-
VCC	P74	P75	-
O, TDO	P75	P76	0
GND	P76	P77	-
I/O	P77	P78	2
I/O, PGCK4 <sup>(1)</sup> , GCK7 <sup>(2)</sup>	P78	P79	5
I/O (CS1 <sup>(2)</sup> )	P79	P80	8
I/O	P80	P81	11
I/O	P81	P82	14
I/O	P82	P83	17
I/O	-	P84	20
I/O	-	P85	23
I/O	P83	P86	26
I/O	P84	P87	29
GND	P1	P88	-

### Notes:

1. 5V Spartan family only
2. 3V Spartan-XL family only
3. The "PWRDWN" on the XCS05XL is not part of the Boundary Scan chain. For the XCS05XL, subtract 1 from all Boundary Scan numbers from GCK3 on (127 and higher).
4. PC84 package discontinued by [PDN2004-01](#)

## XCS10 and XCS10XL Device Pinouts

XCS10/XL Pad Name	PC84 <sup>(4)</sup>	VQ100	CS144 <sup>(2,4)</sup>	TQ144	Bndry Scan
VCC	P2	P89	D7	P128	-
I/O	P3	P90	A6	P129	44
I/O	P4	P91	B6	P130	47
I/O	-	P92	C6	P131	50
I/O	-	P93	D6	P132	53
I/O	P5	P94	A5	P133	56
I/O	P6	P95	B5	P134	59
I/O	-	-	C5	P135	62
I/O	-	-	D5	P136	65
GND	-	-	A4	P137	-
I/O	P7	P96	B4	P138	68
I/O	P8	P97	C4	P139	71
I/O	-	-	A3	P140	74
I/O	-	-	B3	P141	77
I/O	P9	P98	C3	P142	80

## XCS10 and XCS10XL Device Pinouts

XCS10/XL Pad Name	PC84 <sup>(4)</sup>	VQ100	CS144 <sup>(2,4)</sup>	TQ144	Bndry Scan
I/O, SGCK1 <sup>(1)</sup> GCK8 <sup>(2)</sup>	P10	P99	A2	P143	83
VCC	P11	P100	B2	P144	-
GND	P12	P1	A1	P1	-
I/O, PGCK1 <sup>(1)</sup> GCK1 <sup>(2)</sup>	P13	P2	B1	P2	86
I/O	P14	P3	C2	P3	89
I/O	-	-	C1	P4	92
I/O	-	-	D4	P5	95
I/O, TDI	P15	P4	D3	P6	98
I/O, TCK	P16	P5	D2	P7	101
GND	-	-	D1	P8	-
I/O	-	-	E4	P9	104
I/O	-	-	E3	P10	107
I/O, TMS	P17	P6	E2	P11	110
I/O	P18	P7	E1	P12	113
I/O	-	-	F4	P13	116
I/O	-	P8	F3	P14	119
I/O	P19	P9	F2	P15	122
I/O	P20	P10	F1	P16	125
GND	P21	P11	G2	P17	-
VCC	P22	P12	G1	P18	-
I/O	P23	P13	G3	P19	128
I/O	P24	P14	G4	P20	131
I/O	-	P15	H1	P21	134
I/O	-	-	H2	P22	137
I/O	P25	P16	H3	P23	140
I/O	P26	P17	H4	P24	143
I/O	-	-	J1	P25	146
I/O	-	-	J2	P26	149
GND	-	-	J3	P27	-
I/O	P27	P18	J4	P28	152
I/O	-	P19	K1	P29	155
I/O	-	-	K2	P30	158
I/O	-	-	K3	P31	161
I/O	P28	P20	L1	P32	164
I/O, SGCK2 <sup>(1)</sup> GCK2 <sup>(2)</sup>	P29	P21	L2	P33	167
Not Connected <sup>(1)</sup> M1 <sup>(2)</sup>	P30	P22	L3	P34	170
GND	P31	P23	M1	P35	-
MODE <sup>(1)</sup> , M0 <sup>(2)</sup>	P32	P24	M2	P36	173

### CS280

VCC Pins					
E5	E7	E8	E9	E11	E12
E13	G5	G15	H5	H15	J5
J15	L5	L15	M5	M15	N5
N15	R7	R8	R9	R11	R12
R13	-	-	-	-	-
Not Connected Pins					
A4	A12	C8	C12	C15	D1
D2	D5	D8	D17	D18	E15
H2	H3	H18	H19	L4	M1
M16	M18	R2	R4	R5	R15
R17	T8	T15	U5	V8	V12
W12	W16	-	-	-	-
Not Connected Pins (VCC in XCS40XL)					
B5	B15	E3	E18	R3	R18
V5	V15	-	-	-	-

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### XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280 <sup>(2,5)</sup>	Bndry Scan
VCC	P183	P212	VCC <sup>(4)</sup>	VCC <sup>(4)</sup>	-
I/O	P184	P213	C10	D10	86
I/O	P185	P214	D10	E10	89
I/O	P186	P215	A9	A9	92
I/O	P187	P216	B9	B9	95
I/O	P188	P217	C9	C9	98
I/O	P189	P218	D9	D9	101
I/O	P190	P220	A8	A8	104
I/O	P191	P221	B8	B8	107
I/O	-	-	C8	C8	110
I/O	-	-	A7	D8	113
VCC	P192	P222	VCC <sup>(4)</sup>	VCC <sup>(4)</sup>	-
I/O	-	P223	A6	B7	116
I/O	-	P224	C7	C7	119
I/O	P193	P225	B6	D7	122
I/O	P194	P226	A5	A6	125
GND	P195	P227	GND <sup>(4)</sup>	GND <sup>(4)</sup>	-
I/O	P196	P228	C6	B6	128
I/O	P197	P229	B5	C6	131
I/O	P198	P230	A4	D6	134
I/O	P199	P231	C5	E6	137

### XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280 <sup>(2,5)</sup>	Bndry Scan
I/O	P200	P232	B4	A5	140
I/O	P201	P233	A3	C5	143
I/O	-	-	-	D5	146
I/O	-	-	-	A4	149
I/O	P202	P234	D5	B4	152
I/O	P203	P235	C4	C4	155
I/O	P204	P236	B3	A3	158
I/O	P205	P237	B2	A2	161
I/O	P206	P238	A2	B3	164
I/O, SGCK1 <sup>(1)</sup> , GCK8 <sup>(2)</sup>	P207	P239	C3	B2	167
VCC	P208	P240	VCC <sup>(4)</sup>	VCC <sup>(4)</sup>	-
GND	P1	P1	GND <sup>(4)</sup>	GND <sup>(4)</sup>	-
I/O, PGCK1 <sup>(1)</sup> , GCK1 <sup>(2)</sup>	P2	P2	B1	C3	170
I/O	P3	P3	C2	C2	173
I/O	P4	P4	D2	B1	176
I/O	P5	P5	D3	C1	179
I/O, TDI	P6	P6	E4	D4	182
I/O, TCK	P7	P7	C1	D3	185
I/O	-	-	-	D2	188
I/O	-	-	-	D1	191
I/O	P8	P8	D1	E2	194
I/O	P9	P9	E3	E4	197
I/O	P10	P10	E2	E1	200
I/O	P11	P11	E1	F5	203
I/O	P12	P12	F3	F3	206
I/O	-	P13	F2	F2	209
GND	P13	P14	GND <sup>(4)</sup>	GND <sup>(4)</sup>	-
I/O	P14	P15	G3	F4	212
I/O	P15	P16	G2	F1	215
I/O, TMS	P16	P17	G1	G3	218
I/O	P17	P18	H3	G2	221
VCC	P18	P19	VCC <sup>(4)</sup>	VCC <sup>(4)</sup>	-
I/O	-	P20	H2	G4	224
I/O	-	P21	H1	H1	227
I/O	-	-	J4	H3	230
I/O	-	-	J3	H2	233
I/O	P19	P23	J2	H4	236
I/O	P20	P24	J1	J1	239
I/O	P21	P25	K2	J2	242
I/O	P22	P26	K3	J3	245
I/O	P23	P27	K1	J4	248
I/O	P24	P28	L1	K1	251